

Notice of References Cited	Application/Control No. 10/797,261	Applicant(s)/Patent Under Reexamination REES ET AL.	
	Examiner Thomas D. Alunkal	Art Unit .2627	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0114244	08-2002	Kelly et al.	369/53.37
*	B	US-6,442,115	08-2002	Shimoda et al.	369/47.28
*	C	US-5,438,582	08-1995	Hoshino et al.	372/29.014
*	D	US-5,719,835	02-1998	Ishika, Sou	369/44.26
*	E	US-2003/0174606	09-2003	Tsukihashi et al.	369/47.24
*	F	US-6,359,847	03-2002	Shimizu, Toshiki	369/53.26
*	G	US-6,269,059	07-2001	Kuroda et al.	369/47.28
*	H	US-5,309,424	05-1994	Ogawa, Hiroshi	369/47.51
*	I	US-5,579,294	11-1996	Ohta et al.	369/47.31
*	J	US-5,974,021	10-1999	Toda et al.	369/116
*	K	US-5,216,659	06-1993	Call et al.	369/116
*	L	US-5,418,770	05-1995	Ide et al.	369/116
*	M	US-5,463,600	10-1995	Kirino et al.	369/13.24

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/797,261		Applicant(s)/Patent Under Reexamination REES ET AL.	
	Examiner Thomas D. Alunkal		Art Unit 2627	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,495,463	02-1996	Akagi et al.	369/116
*	B	US-5,745,451	04-1998	Mukawa et al.	369/44.29
*	C	US-5,777,964	07-1998	Furuta et al.	369/47.53
*	D	US-5,790,491	08-1998	Jaquette et al.	369/47.53
*	E	US-6,154,433	11-2000	Hoshino et al.	369/112.04
*	F	US-6,414,932	07-2002	Kaku et al.	369/116
*	G	US-6,442,118	08-2002	Hoshino et al.	369/47.3
*	H	US-6,483,791	11-2002	Asada et al.	369/59.11
*	I	US-6,487,154	11-2002	Kurebayashi et al.	369/53.26
*	J	US-6,558,987	05-2003	Lee, Seong-Su	438/149
*	K	US-6,636,472	10-2003	Kurebayashi et al.	369/116
*	L	US-6,654,328	11-2003	Kaku et al.	369/53.26
*	M	US-6,674,702	01-2004	Asada et al.	369/47.52

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/797,261

Applicant(s)/Patent Under
Reexamination
REES ET AL.

Examiner

Thomas D. Alunkal

Art Unit

2627

Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,687,208	02-2004	Asada et al.	369/59.11
*	B	US-2002/0126609	09-2002	Kaku et al.	369/53.26
*	C	US-2002/0186628	12-2002	Hoshino et al.	369/47.3
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.